

2N5564 MONOLITHIC DUAL **N-CHANNEL JFET**



Linear Systems replaces discontinued Siliconix & National 2N5564

The 2N5564 are monolithic dual JFETS. The monolithic dual chip design reduces parasitics and gives better performance at very high frequencies while ensuring extremely tight matching. These devices are an excellent choice for use as wideband differential amplifiers in demanding test and measurement applications. The 2N5564 is a direct replacement for discontinued Siliconix and National 2N5564.

The hermetically sealed TO-71 is well suited for military and harsh environment applications. (See Packaging Information).

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- Wideband Differential Amps
- High-Speed, Temp-Compensated Single-**Ended Input Amps**
- **High-Speed Comparators**
- Impedance Converters and vibrations detectors.

FEATURES								
Improved Direct Replacement for SILICONIX & NATIONAL 2N5564								
HIGH GAIN 7500μmho MINIMUM								
LOW "ON" RESISTANCE 100Ω MAXIMUM								
ABSOLUTE MAXIMUM RATINGS ¹								
@ 25°C (unless otherwise noted)								
Maximum Temperatures								
Storage Temperature	-65°C to +200°C							
Operating Junction Temperature	-55°C to +125°C							
Maximum Power Dissipation								
Device Dissipation (Each transistor)	325mW							
Continuous Power Dissipation (Total)	650mW							
Maximum Currents								
Gate Current	50mA							
Maximum Voltages								
Gate to Drain	-40V							
Gate to Source -40V								
Gate to Gate ±80V								

MATCHING CHARACTERISTICS @ 25°C (unless otherwise stated)

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
V _{GS1} - V _{GS2}	Differential Gate to Source Cutoff Voltage			5	mV	$V_{DG} = 15V, I_D = 2mA$
$\Delta V_{GS1} - V_{GS2} / \Delta T$	Differential Gate to Source Cutoff			10	μV/°C	$V_{DG} = 15V, I_{D} = 2mA$
	Voltage Change with Temperature					T _A = -55°C to +125°C
I _{DSS1} / I _{DSS2}	Gate to Source Saturation Current Ratio	0.95		1	%	$V_{DS} = 10V, V_{GS} = 0V$
	107					7
I _{G1} – I _{G2}	Differential Gate Current			20	nA	$V_{DG} = 10V, I_D = 5mA$ $T_A = +125^{\circ}C$
						T _A = +125°C
g_{fs1}/g_{fs2}	Forward Transconductance Ratio ²	0.95		1	%	$V_{DS} = 15V, I_D = 2mA, f = 1kHz$

ELECTRICAL CHARACTERISTICS @ 25°C (unless otherwise noted)

SYMBOL	CHARACTERISTICS	MIN.	TYP.	MAX.	UNITS	CONDITIONS
BV_{GSS}	Gate to Source Breakdown Voltage	-40				$I_{G} = -1\mu A$, $V_{DS} = 0V$
$V_{GS(off)}$	Gate to Source Cutoff Voltage	-0.5		-3	V	$V_{DS} = 15V, I_{D} = 1nA$
$V_{GS(F)}$	Gate to Source Forward Voltage			1		$I_G = 2mA, V_{DS} = 0V$
I _{DSS}	Gate to Source Saturation Current ³	5		30	mA	$V_{DS} = 15V, V_{GS} = 0V$
I _{GSS}	Gate Leakage Current ³			-200	nA	$V_{GS} = -20V, V_{DS} = 0V, 150$ °C
g fs	Forward Transconductance	7500		12500		V_{DG} = 15V, I_D = 2mA, f = 1kHz
		7000			μS	$V_{DG} = 15V$, $I_D = 2mA$, $f = 100MHz$
g _{os}	Output Conductance			45		$V_{DG} = 15V$, $I_{D} = 2mA$, $f = 1kHz$
C _{ISS}	Input Capacitance			5	pF	$V_{DG} = 15V$, $I_D = 2mA$, $f = 100MHz$
C_{RSS}	Reverse Transfer Capacitance			12		
NF	Noise Figure			1	dB	$V_{DG} = 15V$, $I_D = 2mA$, $f = 10Hz$, $R_G = 1M\Omega$
_	Equivalent Input Noise Voltage			50	nV/√Hz	$V_{DG} = 15V$, $I_D = 2mA$, $f = 10Hz$
e_n						

Notes: 1. Absolute Maximum ratings are limiting values above which serviceability may be impaired 2. Pulse Test: PW ≤ 300µs Duty Cycle ≤ 3%

3. Assumes smaller value in numerator

TO-71 (Top View)

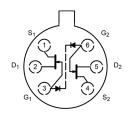


Available Packages:

2N5564 in TO-71 2N5564 available as bare die

Please contact Micross for full package and die dimensions:

Email: chipcomponents@micross.com Web: www.micross.com/distribution.aspx



This is trial version

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